

Pintail Technologies Announces SwifTest™ 5.2

Semiconductor Test Software Suite Supports Teradyne's FLEX, Adds Significant Productivity Improvements

DALLAS (October 24, 2005) - Pintail Technologies, a breakthrough semiconductor test solutions provider, announced today the release of SwifTest™ 5.2, the latest version of its real-time statistical sampling software suite for semiconductor testing. This new version of its signature product expands Pintail's capabilities to reduce test cost and improve quality and test efficiency in real-time.

The SwifTest family includes three primary optional modules:

- **SwifTest-Monitor** captures test results in real-time from the tester and preprocesses the parametric data. With support for local, real-time alerts, it is a pre-requisite for Pintail's sampling, outlier detection and TestScape database management system (DBMS).
- **SwifTest-MX**, Pintail's patented, real-time, statistical sampling tool has proven to reduce test time by up to 40 percent in mixed-signal production at both probe and final test.
- **SwifTest-AQ**, Pintail's dynamic outlier detection tool for reducing DPM (defect per million) by applying parts average testing (PAT) in real-time is popular for testing automotive electronics at both probe and final test.

Key new features in the SwifTest 5.2 release include:

Teradyne Flex Support: SwifTest is now available for installation on Teradyne's latest FLEX ATE platforms, increasing Pintail's platform support to include most Teradyne systems, LTX Fusion and Cadence systems and Agilent's 93K.

Part Average Testing (PAT) Enhancements: The automotive industry has responded rapidly to the availability of Pintail's real-time PAT solution that dynamically eliminates outliers during test and thus reduces field failures. **Geographic Wafer Analysis Option** has been added for optional cluster analysis on wafers during on-line PAT processing, including four modes for performing neighborhood:

- Failing Die Weighting
- PAT Outlier Die Weighting
- Software Bin Die Weighting
- Hardware Bin Die Weighting

SwifTest Commander: SwifTest Commander is a Web-based information console for managing all running instances of SwifTest across a test floor. Information about current license usage, current processing lots and specific statistical information is available to facilitate management of multiple installations of SwifTest.

Device Profile Designer: New features added to the Device Profile Designer streamline the preparation of test programs for real-time sampling or real-time PAT.

Agilent Data Conduit: The Agilent Data Conduit has been enhanced with improved functionality to support the Agilent 93000 tester platform.

New Triggers and Alerts: Real-time monitoring now includes capabilities to monitor site-to-site variations, lot yield and outlier counts, in addition to the earlier triggers and alerts.

Lot Classification: SwifTest now automatically classifies lots as First Pass, Correlation, Setup, Engineering, Retest, QA or unknown types to support downstream applications like Pintail's TestScape database management system.

About Pintail Technologies

Pintail Technologies is a semiconductor test improvement and yield learning company that provides breakthrough software to reduce the cost of test and increase production output and quality through existing test equipment and programs. Pintail has created the first test improvement solutions to combine real-time test process control capabilities with innovative analytical programs in an integrated software suite designed for speed and accuracy. Fabless and integrated device manufacturers worldwide, in collaboration with leading assembly and test suppliers use Pintail tools to increase competitive advantage and improve responsiveness to test issues. Pintail has sales offices in Dallas, Austin, San Jose, Seoul, Singapore, Taiwan, Munich and Switzerland. See more information at www.pintail.com.

